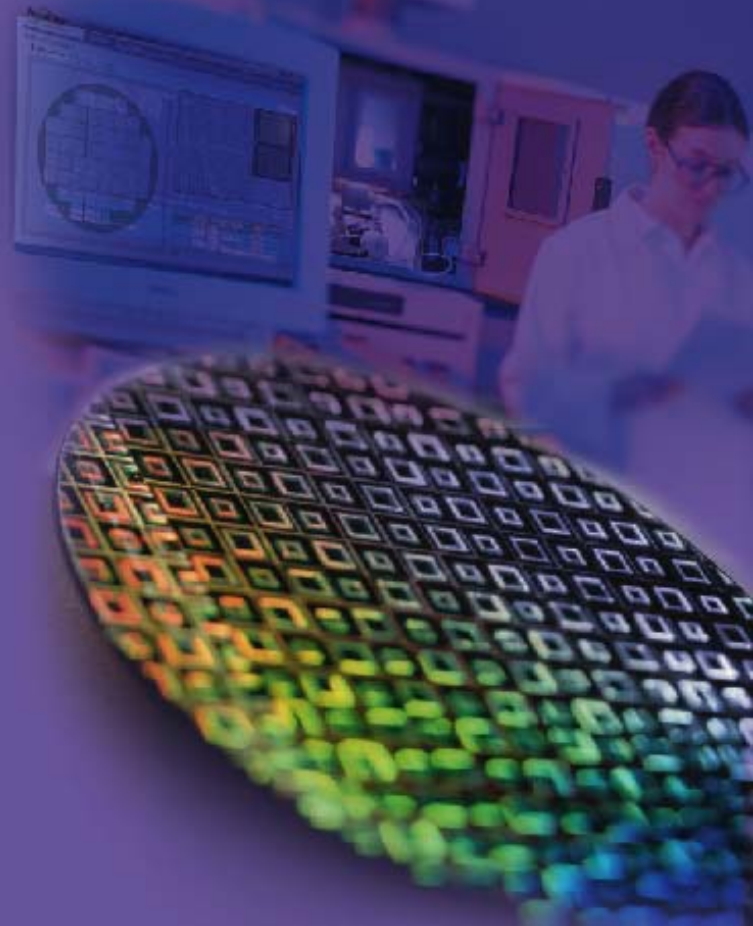




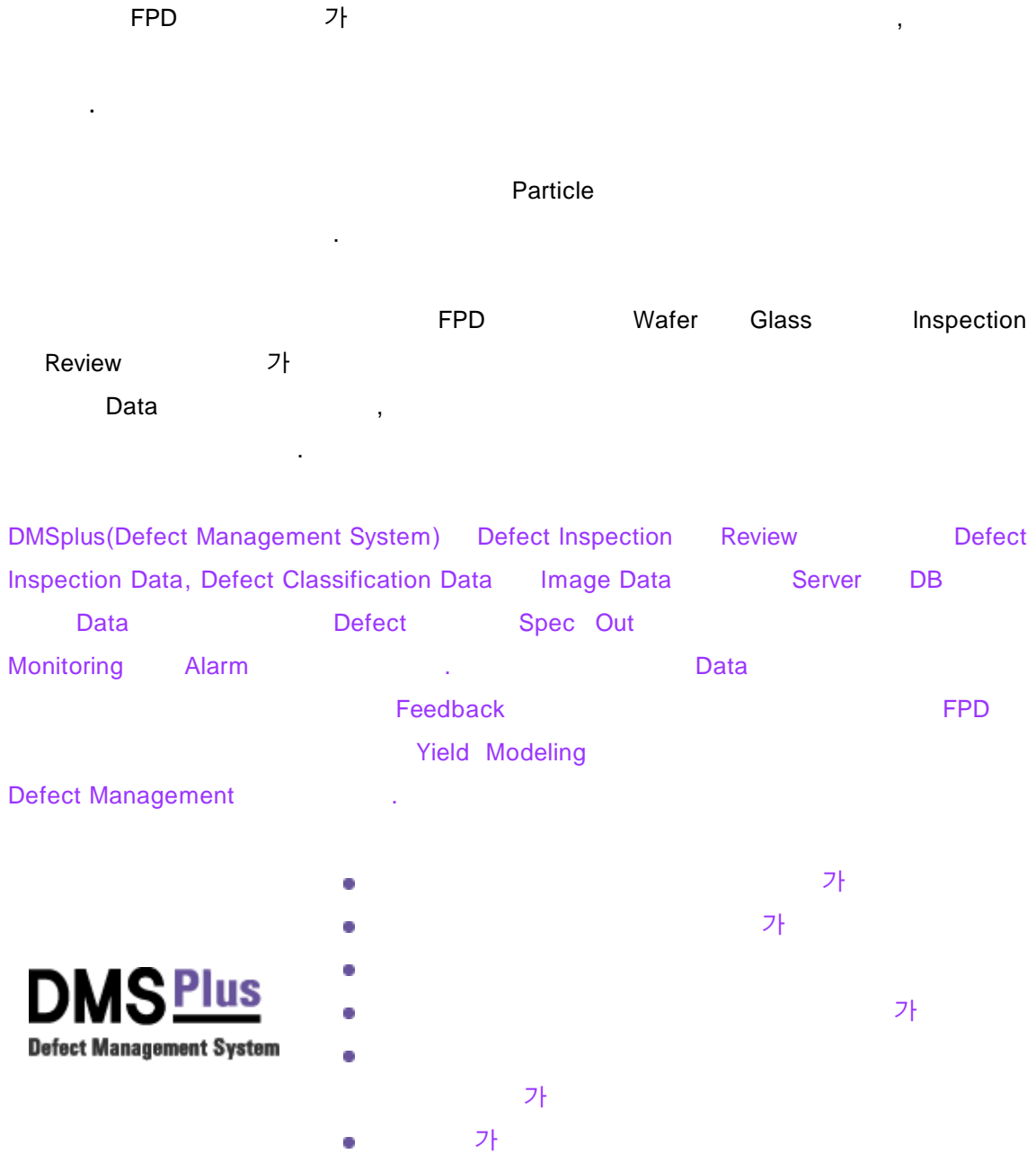
*Like to visualize uprising yield enhancement  
and accurate yield prediction?  
DMSplus provides the most efficient Yield Analysis  
and Defect Management Solution  
for semiconductor/FPD industry*

# DMSPlus

Defect Management System



## Defect Management System





DMSplus

- Probe Test 가
- Memory Test 가
- Random Defect Yield Loss 가 Systematic Yield Loss Yield
- Modeling 가
- 가

DMSplus

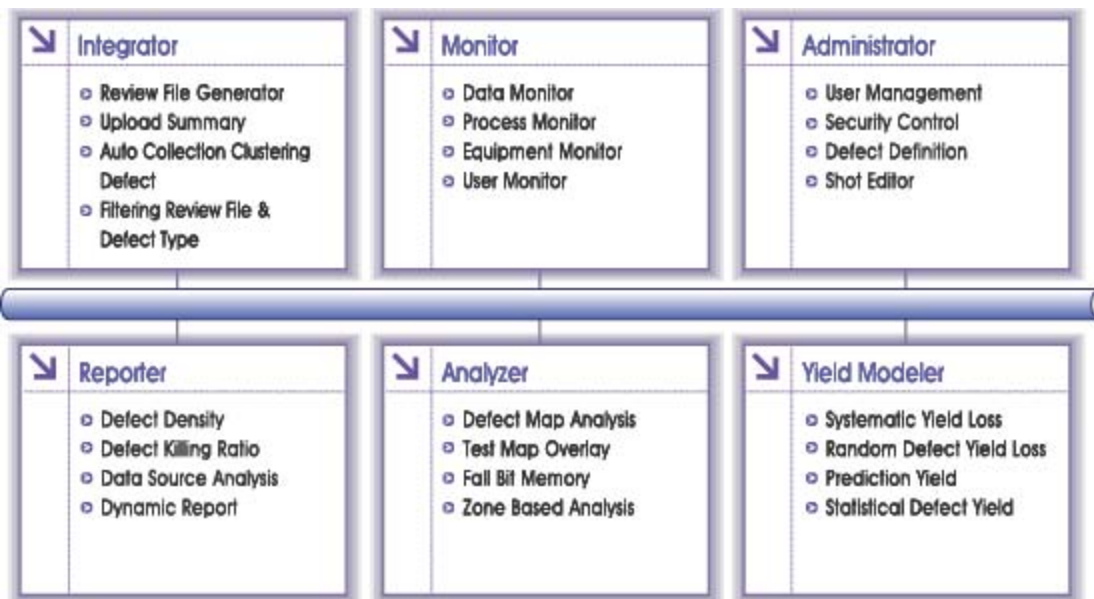
IT FPD

- Automatic Defect Map Design & Drawing : Recipe Defect Map Drawing
- Real Size Defect Map Drawing : 1/1000  $\mu\text{m}$  Real Size Drawing
- Defect Size Scope Handling : Defect Defect Size Drawing
- No Limited Zoom-In/Out : Defect Map 가
- Standardization Data Interface : Defect Inspection/Review Data Result DB
- Various Data Collection Method : FPT(Get, Receive), NFS Interface Protocol
- Custom Review File Generation : 가 Filtering Defect Data Review Review Source File 가



Administrator	Monitor	Integrator	Reporter	Analyzer	Yield Modeler
Shot Editor	Data Loss Monitoring	Data Process	Data Source Analysis	Defect Map Analysis	Systematic Yield Loss
Defect Class Definition	Process Monitoring	Image Data Process	Defect Density	Shot Map Analysis	Random Defect Yield Loss
Coloring by Size & Type	Equipment Monitoring	Statistic Data Process	Defect Killing Ratio	Repeat Defect Analysis	Statistical Defect Yield
Equipment Setup	User Monitoring	MES Data Gathering	Dynamic Report	View Defect Image	Defect Control Level Table
Custom Environment		Custom KLARF Generate	Trend Report	Multi Layer Overlay	Prediction Yield
User Management		Manual Data Gathering	User Report	Multi Defect Map Overlay	
Menu Grade Setting		FGA Data Linker	Cross Analysis	Defect Distribution	
				Test Map Overlay	
				Fail Bit Map Analysis	
				Zone Based Defect Map	

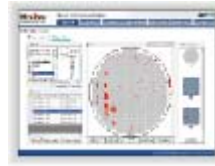
## DMSplus Module



## DMSplus

➤ Defect Map Analysis

- Coloring by Defect Type & Size
- Defect Density Map
- Defect Image Gallery
- Drag Defect Position



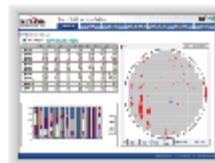
### ↳ Map Overlay

- Multi Defect Map Overlay
- Multi Layer Defect Map Overlay
- Test Map Overlay



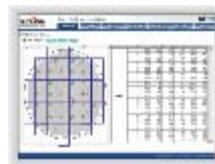
### ↳ DSA(Defect Source Analysis)

- Time Based Defect Source Analysis
- DSA by Type & Size
- Carry Over & Adder Defect Analysis



### ↳ Repeat Defect Analysis

- Shot Based Repeating Defect
- Design Based Repeating Defect
- Specification Repeating Defect
- Glass / Wafer Based Repeating Defect



### ↳ FBM(Fail Bit Memory) Overlay

- Automatic Collection Matching Point
- Drill Down Bit Map Analysis
- Glass/Wafer, Shot, Die & Cell



### ↳ Chart & Dynamic Report

- ▣ Display Various Chart
- ▣ Display Box Plot
- ▣ Customization Batch / Dynamic Report
- ▣ Main Process Equipment Report
- ▣ Defect Killing Ratio / Defect Density Report
- ▣ Equipment Utilization Report



### ▾ Data & Equipment Interface

- ▣ Interface with Multiple Processing
- ▣ Result Data Common Formatting
- ▣ Customization of Review Source
- ▣ Image Processing



### ▾ Yield Modeling

- ▣ Statistical Defect Yield
- ▣ Defect Control Level Table
- ▣ Systematic Yield Loss
- ▣ Random Defect Yield Loss
- ▣ Prediction Yield



### DMSplus

- ▣ Defect Monitoring Data
- ▣ Defect Data Monitoring 가
- ▣ Defect Management
- ▣ Utilization
- ▣ Defect Data Report Process
- ▣ Data(Process, EDS Test, Memory Test, Equipment) 가
- ▣ Yield Modeling 가
- ▣ Systematic Yield Loss Random Defect Yield Loss 가
- ▣ 가